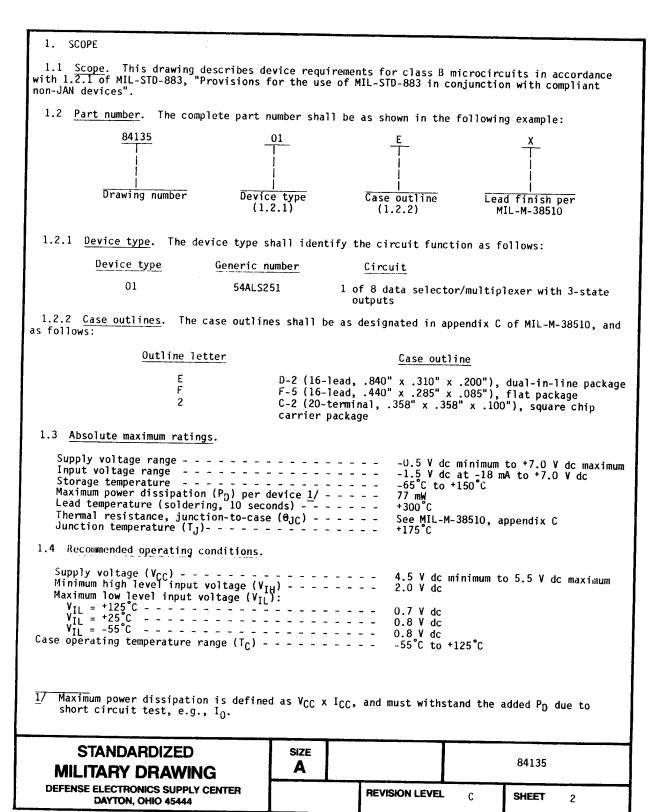
											RE\	/ISIC	ONS													
TR	T						D	ESC	RIPTI	ON									DATE	(YR-I	MO-DA)	API	PROV	ED	
В	Change	maxi	mum	10	w 1	evel	in	put	vol	tage	, (۷ _{IL})	to	0.7	7 V	dc.			1987	API	R 28			1	Lie	,
	Delete on pro			£	0.00		2002	tion	de [°] evis	lay e to	tim mi	es. lita	Chi ry	ange drav	e ma ving	ximu	um rmat	.				r	7.4	. 7		
C	Footno	Change maximum low level input voltage, (V _{IL}) to 0.7 V dc. Delete minimum from propagation delay times. Change maximum on propagation delay times. Revise to military drawing format. Split V _{IL} into temperatures. Change propagation delays. Add footnotes to table 1. Add figure 4. Editorial changes throughout. Change in Table II. Add CAGE 27014 to case 2.																								
Cl	JRRE	NT	C,	AC T	3E	C	OE	ÞΕ	67	26	8	1		1		Y	<u> </u>									
		NT 	c.	AC T	SE	C	OE	E	67	26	8															
REV		NT	C,	AC T	Æ	C	OE	ΡE	67	26	8															
REV SHES	ΞT	NT	C,	AC T	Œ	C	OE	ÞΕ	67	26	8															
REV SHEE REV SHEE	ΞT		C	AC 	Æ	C	OE c	DE c	67	26	8	C	c	c	C	c	c	C								
REV SHEE REV SHEE	ET ET				GE			c			c	C 7	C 8		<u>C</u>		C 12									
REV SHEE REV	ET STATUS		REV		Æ	C 1	C 2	C 3	C 4	C	c	_			10	11	12	13 ELE	CTRO		S SUII		/ CEN	VTER		
REV SHEE SHEE REV OF S	ET STATUS	RDI	REV	T	GE	C 1	C 2	C 3	C 4	C	c	_		9	10 MICF LOW	DEFE ROCI POW	12 NSE	T, I	CTROTON DIGI	TAL	S SUI O 454	444 POLA	AR,	ADVA	NCE	D

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

- Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
- 3.2.4 Switching circuit and waveforms. The switching circuit and waveforms shall be as specified on figure 4.
 - 3.2.5 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

STANDARDIZED MILITARY DRAWING	SIZE A		84135		
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL	- C	SHEET 3	

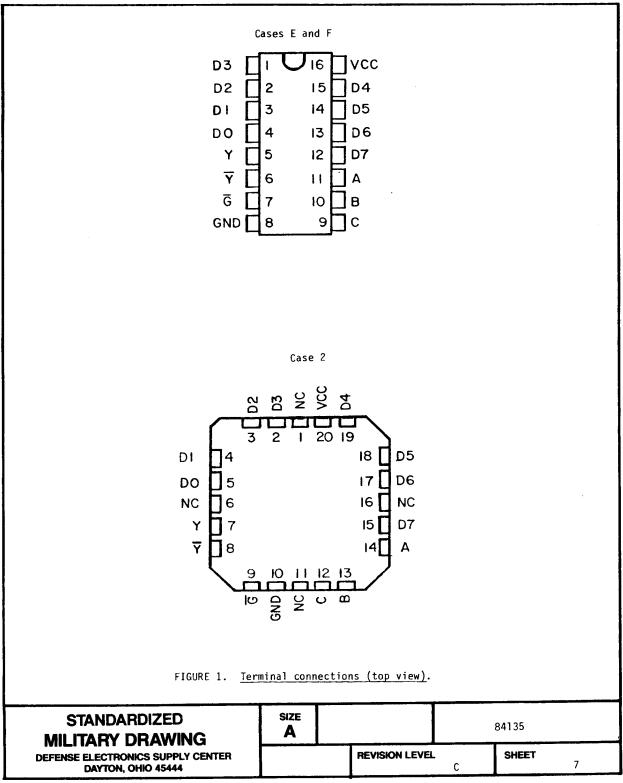
TA	ABLE I. <u>E1</u>	ectrical performance	e characteris	tics. 1/			
Test	Symbol	Condit Condit -55°C < T _C unless otherwi	ions < +125°C	Group A sub-		imits	Un ·
High level output voltage	I v _{OH}	1VCC = 4.5 V		1 1	Min	Max	+-
night level output voltage	*OH 	V _{IL} : at +125°C = 0.7 V	I _{OH} = -0.4 m/ 	 	2.5		
		at -55°C = 0.8 V at +25°C = 0.8 V 2/	1	т і	2.4		†
Low level output voltage	v _{OL}	V _{CC} = 4.5 V I _{OL} = 12 mA V _{LL} = 2.0 V	V _{IL} = 0.7 V	2		0.4	V
	<u> </u>	VIH = 2.0 V	V _{IL} = 0.8 V	1,3		! 	
Input clamp voltage	VIC	V _{CC} = 4.5 V I _{IN} = -18 mA		1,2,3		-1.5	٧
High level input current	I _{IH1}	V _{CC} = 5.5 V V _{IN} = 2.7 V Unused inputs = 0).0 V	1,2,3		20	μА
	I _{IH2}	V _{CC} = 5.5 V V _{IN} = 7.0 V Unused inputs = 0).0 V	1, 2, 3		0.1	mA
Low level input current	II _{IL}	V _{CC} = 5.5 V V _{IN} = 0.4 V Unused inputs are	e > 4.5 V	1, 2, 3		-0.1	mA
Output current	I ₀	V _{CC} = 5.5 V V _{OUT} = 2.25 V	<u>3</u> /	1, 2, 3	-30	-112	mA
Supply current	ICC	V _{CC} = 5.5 V V _{IN} ≤ 0.4 V	Enabled	1, 2, 3		10	mA
		V _{CC} = 5.5 V V _{IN} > 4.5 V	Disabled	1, 2, 3		14	mA
Offstate output current	IOZH	V _{CC} = 5.5 V V _{OUT} = 2.7 V		1, 2, 3		20	 μ A
	IOZL	V _{CC} = 5.5 V V _{OUT} = 0.4 V		1, 2, 3		-20 	μ A
ee footnotes at end of tabl	e.			1		<u> </u>	<u></u>
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TABLE I.	Electrical	performance characteristics -		d. <u>1</u> /		
Test	Symbol	Conditions	Group A	Ļi	mits	 Unit
		Conditions -55°C < T _C < +125°C unless otherwise specified	sub- groups	Min	Max	T
Funtional tests		See 4.3.1c 4/	7,8			I I
Propagation delay time A, B, C to Y	t _{PLH1}	V _{CC} = 4.5 V to 5.5 V C _L = 50 pF	9,10,11	1	19	ns
	t _{PHL1}	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	9,10,11	8	32	-
Propagation delay time A, B, C to Y	it _{PLH2}	See figure 4 	9,10,11	8	30.5	ns
	t _{PHL2}	 	9,10,11	7	23.5	-
Propagation delay time Any D to Y	tpLH3		9,10,11	2	11	ns
	t _{PHL} 3		9,10,11	3	21	
Propagation delay time Any D to Y	tpLH4	1	9,10,11	3	20.5	ns
	t _{PHL4}	 	9,10,11	3	16	
Output enable time G to Y	t _{PZH1}	 	9,10,11	3	15	ns
	t _{PZL1}	 	9,10,11	3	18]
Output disable time G to Y	t _{PHZ1}		9,10,11	2	10	ns
	t _{PLZ1}	1	9,10,11	1	13	
Output enable time G to Y	t _{PZH2}	 - -	9,10,11	3	15	ns
	t _{PZL2}	 	9,10,11	3	17	
Output disable time G to Y	t _{PHZ2}	 	9,10,11	2	10	ns
	t _{PL Z2}	 	9,10,11	1	13	
See footnotes on other pag	je.					
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- 1/ Unused inputs that do not directly control the pin under test must be > 2.5 V or \leq 0.4 V. No unused inputs shall exceed 5.5 V or go less than 0.0 V. No inputs shall be floated.
- 2/ All outputs must be tested. In the case where only one input at V_{IL} maximum or V_{IH} minimum produces the proper output state, the test must be performed with each input being selected as the V_{IL} maximum or the V_{IH} minimum input.
- $\frac{3}{2}$ The output conditions have been chosen to produce a current that closely approximates one half of the true short circuit output current, I_{OS} . Not more than one output will be tested at one time and the duration of the test condition shall not exceed 1 second.
- $\underline{4}/$ Functional tests shall be conducted at input test conditions of GND $\underline{<}$ V_{IL} $\underline{<}$ V_{OL} and V_{OH} $\underline{<}$ V_{IH} $\underline{<}$ V_{CC}.
- $\underline{5}/$ Propagation delay limits are based on single output switching. Unused inputs = 3.5 V or $\underline{<}$ 0.3 V.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- $\frac{4.1}{4.1}$ Sampling and inspection. Sampling and inspection procedures shall be in accordance with section $\frac{4}{4}$ of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 7 and 8 tests shall verify the truth table as specified on figure 2 herein.

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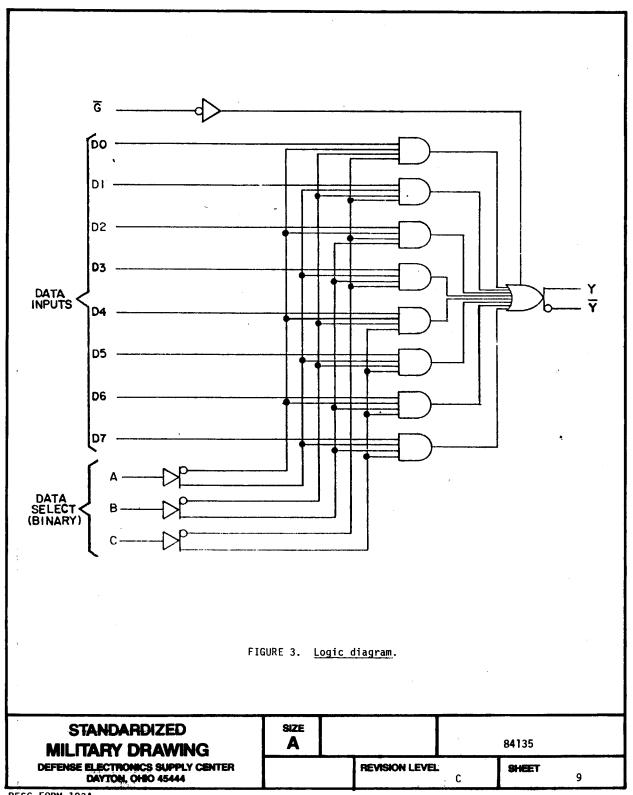
 		Inpu	l Outputs				
Se	Select Strobe						
<u>i</u> c	В	Α	G	Y	Ϋ́I		
X	X	X	 H	Z	z		
L	L	L) L	DO	00		
_	L	Н	! L	D1	DI I		
L	Н	L	L	D2	D2		
L	Н	Н	, L	D3	<u>p3</u>		
Н	L	L	į	D4	D4		
Н	L	Н	L	D5	D5		
Н	Н	L	L	D6	<u>D6</u>		
Н	Н	н	 	D7	D7		

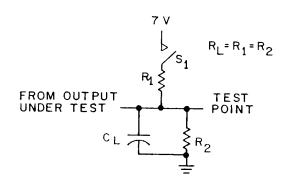
DO, D1 ... D7 = the level of the respective D input.

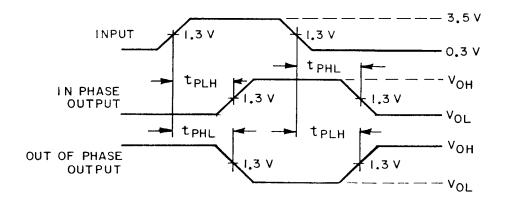
H = High voltage level
L = Low voltage level
X = Irrelevant

FIGURE 2. Truth table.

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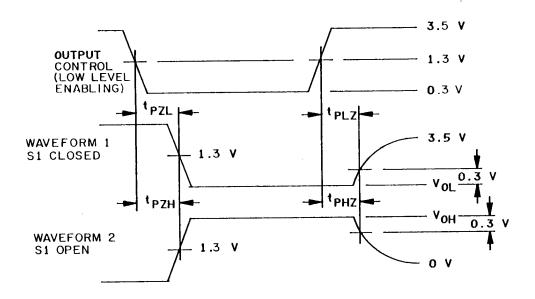




PROPAGATION DELAY TIMES

FIGURE 4. Switching circuit and waveforms.

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ENABLE AND DISABLE TIMES

NOTES:

- 1. C_L includes probe and jig capacitance.
- 2. When measuring propagation delay times of three-state outputs, switch S1 is open.
- When measuring propagation delay times of three-state outputs, switch SI is open.
 Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
 Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 All input pulses have the following characteristics: PRR < 10 MHz, duty cycle = 50 percent, t_r = t_f = 3 ns ±1 ns.
- 5. The outputs are measured one at a time with one input transition per measurement.

FIGURE 4. Switching circuit and waveforms - Continued.

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4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A or D using the circuit submitted with the certificate of (see 3.5 herein).
 - (2) $T_A = +125$ °C, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004) 	
Final electrical test parameters (method 5004) 	1*,2,3,7,8,9, 10,11
Group A test requirements (method 5005) 	1,2,3,7,8,9, 10,11
Groups C and D end-point electrical parameters (method 5005) 	1, 2, 3

^{*} PDA applies to subgroup 1.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1</u> /
8413501EX	01295	SNJ54ALS251J 54ALS251J/883
8413501FX	01295	 SNJ54ALS251W
84135012X	01295 27014	SNJ54AL S251FK 54AL S251E / 883

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE vendor name and address

01295
Texas Instruments, Inc. P.O. Box 6448 Midland, TX 79701

27014
National Semiconductor

National Semiconductor 2900 Semiconductor Drive Santa Clara, CA 95051

STANDARDIZED	
MILITARY [DRAWING

SIZE A 84135

REVISION LEVEL SHEET 13

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444